Search Notes			

Application/Control No.	Applicant(s)/Patent u	Applicant(s)/Patent under Reexamination	
10/542,394	FUJITA, KATSUFUSA		
Examiner	Art Unit		
Tran N. Nguyen	2834		

SEARCHED			
Class	Subclass	Date	Examiner
310	216 217 254 261	7/1/06	na
	261	*	₩
336	210	7/4/	5/
	2/2	1/00	1/2/
	219	1 8	
	234.	V	B
update	asole	12/12/06	DATO
<del></del>			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
-				
· · · · · · · · · · · · · · · · · · ·				
	<u> </u>	<del> ,</del>		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
·			
	,		
		<del></del>	